



### **COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET**

### **Product Summary**

Device	V <sub>(BR)DSS</sub>	R <sub>DS(on) max</sub>	I <sub>D</sub> T <sub>A</sub> = +25°C
Q1	60V	40mΩ @ V <sub>GS</sub> = 10V	6.5 A
N-Channel	60 V	55mΩ @ V <sub>GS</sub> = 4.5V	5.6 A
Q2	-60V	110mΩ @ V <sub>GS</sub> = -10V	-3.9 A
P-Channel	-60 <i>V</i>	130mΩ @ V <sub>GS</sub> = -4.5V	-3.6 A

### **Description and Applications**

This new generation MOSFET has been designed to minimize the onstate resistance ( $R_{DS(ON)}$ ) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

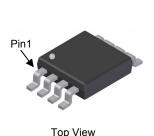
- DC-DC Converters
- · Power Management Functions
- Backlighting

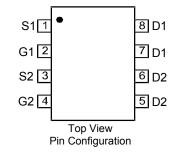
### **Features and Benefits**

- Low Input Capacitance
- Low On-Resistance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

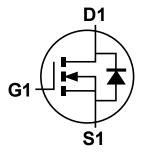
### **Mechanical Data**

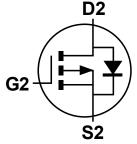
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound.
   UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Tin Finish annealed over Copper leadframe.
   Solderable per MIL-STD-202, Method 208 (2)
- Weight: 0.074 grams (approximate)





SO-8





Q1 N-Channel MOSFET

Q2 P-Channel MOSFET

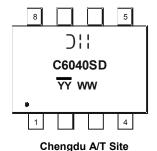
### **Ordering Information** (Note 4)

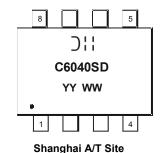
Part Number	Case	Packaging	
DMC6040SSD-13	SO-8	2,500/Tape & Reel	

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- See http://www.diodes.com/quality/lead\_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

# **Marking Information**





);; = Manufacturer's Marking C6040SD = Product Type Marking Code YYWW = Date Code Marking YY or YY = Year (ex: 14= 2014) WW = Week (01 - 53)

YY = Date Code Marking for SAT (Shanghai Assembly/ Test site)
YY = Date Code Marking for CAT (Chengdu Assembly/ Test site)



# **Maximum Ratings** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Q1	Q2	Units		
Drain-Source Voltage	$V_{DSS}$	60	-60	V		
Gate-Source Voltage	V <sub>GSS</sub>	±20	±20	V		
Continuous Preis Correct (Nata CVV - 40V	Steady State	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	5.1 4.1	-3.1 -2.5	А
Continuous Drain Current (Note 6) V <sub>GS</sub> = -10V	t<10s $T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$		I <sub>D</sub>	6.5 5.2	-3.9 -3.1	А
Maximum Body Diode Forward Current (Note 6)	Is	2.1	-2.1	Α		
Pulsed Drain Current (10µs pulse, duty cycle = 1	I <sub>DM</sub>	28	-19	Α		
Avalanche Current (Note 7) L = 0.1mH	I <sub>AS</sub>	17.2	-17.6	Α		
Avalanche Energy (Note 7) L = 0.1mH	E <sub>AS</sub>	14.7	15.4	mJ		

# Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 5)	T <sub>A</sub> = +25°C	П	1.24	W
Total Power Dissipation (Note 5)	T <sub>A</sub> = +70°C	$P_{D}$	0.8	
Thormal Booistanes, Junction to Ambient (Note 5)	Steady state	D	101	°C/W
Thermal Resistance, Junction to Ambient (Note 5)	t < 10s	$R_{\theta JA}$	61	
Total Dower Dissipation (Note 6)	T <sub>A</sub> = +25°C	Б	1.56	W
Total Power Dissipation (Note 6)	T <sub>A</sub> = +70°C	P <sub>D</sub>	1.0	
Thermal Begintanes, Junction to Ambient (Note 6)	Steady state	D	80	°C/W
Thermal Resistance, Junction to Ambient (Note 6)	t<10s	$R_{\theta JA}$	49	
Thermal Resistance, Junction to Case (Note 6)		$R_{ heta JC}$	14.7	
Operating and Storage Temperature Range		T <sub>J,</sub> T <sub>STG</sub>	-55 to +150	°C

# Electrical Characteristics N-Channel Q1 (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	60	_	_	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	1	μA	V <sub>DS</sub> = 48V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>		_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	V <sub>GS(th)</sub>	1	_	3	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Static Drain-Source On-Resistance	В		33	40	mO.	$V_{GS} = 10V, I_D = 8A$
Static Drain-Source On-Resistance	R <sub>DS (ON)</sub>	_	37	55	mΩ	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 5A
Diode Forward Voltage	V <sub>SD</sub>	_	0.7	1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 1A
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C <sub>iss</sub>		1130	_		
Output Capacitance	Coss	_	69	_	pF	$V_{DS} = 15V$ , $V_{GS} = 0V$ f = 1.0MHz
Reverse Transfer Capacitance	C <sub>rss</sub>		42			
Gate Resistance	R <sub>G</sub>	_	1.7	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$
Total Gate Charge (V <sub>GS</sub> = 10V)	Qg		20.8	_		
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Qg		9.4	_	20	\\ - 20\\ \ \ - 4.2\\
Gate-Source Charge	Q <sub>gs</sub>		3.3	_	nC	$V_{DS} = 30V, I_D = 4.3A$
Gate-Drain Charge	$Q_{gd}$		3.0	_		
Turn-On Delay Time	t <sub>D(on)</sub>		3.6	_		
Turn-On Rise Time	t <sub>r</sub>		1.8	_		$V_{GS} = 10V, V_{DD} = 30V, R_G = 6\Omega,$
Turn-Off Delay Time	t <sub>D(off)</sub>		20.1	_	nS	I <sub>D</sub> = 4.3A
Turn-Off Fall Time	t <sub>f</sub>		4.3	_		
Body Diode Reverse Recovery Time	t <sub>rr</sub>	_	14.2	_	nS	I <sub>S</sub> = 4.3A, dI/dt = 100A/µs
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>		7.5	_	nC	I <sub>S</sub> = 4.3A, dI/dt = 100A/µs

otes: 5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.

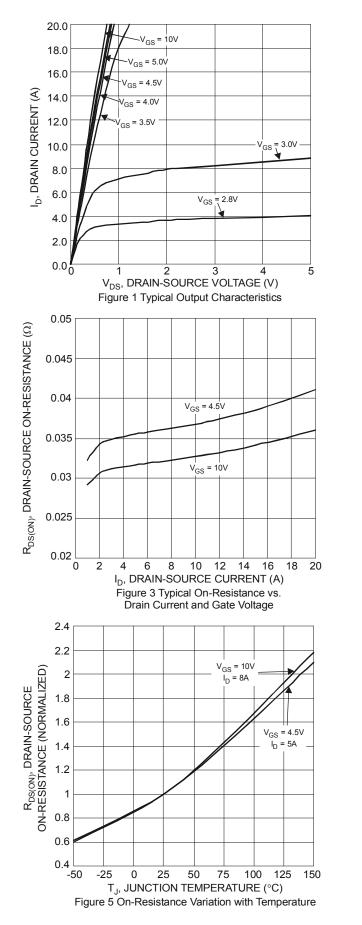
6. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

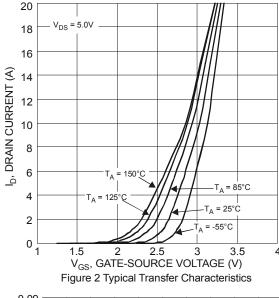
7. UIS in production with L = 0.1mH, starting  $T_A = +25$ °C.

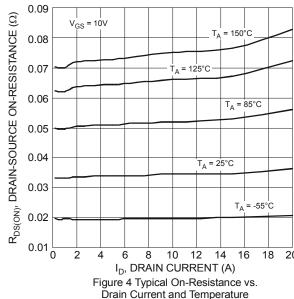
8. Short duration pulse test used to minimize self-heating effect.

9. Guaranteed by design. Not subject to product testing.









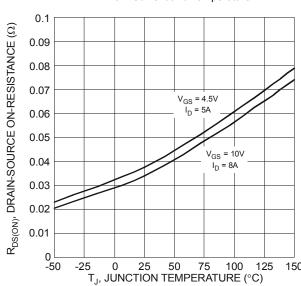


Figure 6 On-Resistance Variation with Temperature



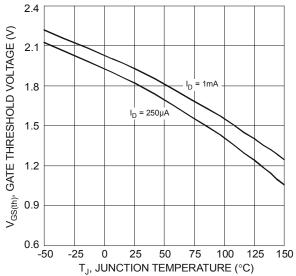
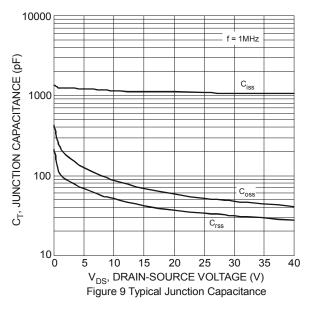
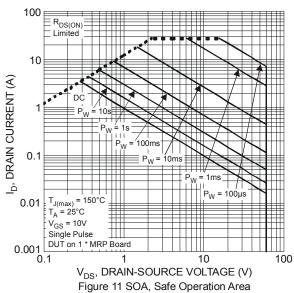
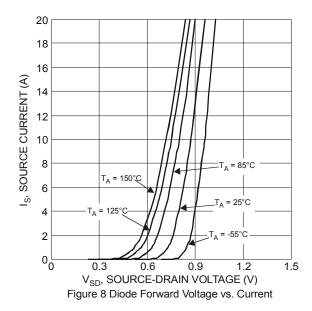
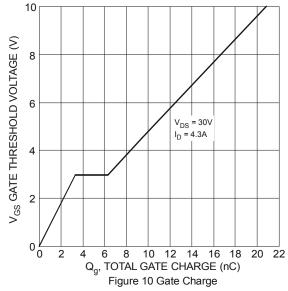


Figure 7 Gate Threshold Variation vs. Ambient Temperature

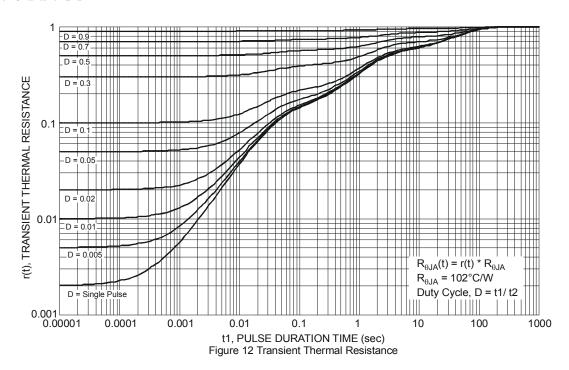












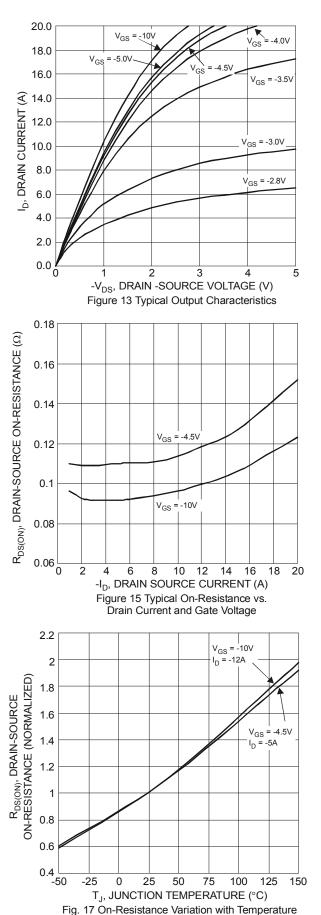
## Electrical Characteristics P-Channel Q2 (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-60	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	-1	μΑ	$V_{DS} = -48V, V_{GS} = 0V$
Gate-Source Leakage	I <sub>GSS</sub>	_	_	100	nA	$V_{GS} = \pm 16V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	V <sub>GS(th)</sub>	-1		-3	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
Static Drain-Source On-Resistance	D		86	110	mΩ	$V_{GS} = -10V, I_D = -4.5A$
Static Dialii-Source Oil-Resistance	R <sub>DS (ON)</sub>		98	130		$V_{GS} = -4.5V, I_D = -3.5A$
Diode Forward Voltage	$V_{SD}$	_	-0.7	-1.2	V	$V_{GS} = 0V, I_{S} = -1A$
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	Ciss		1030			V <sub>DS</sub> = -30V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	Coss		49.1		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>		38.7			
Gate Resistance	$R_G$		13.6	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$
Total Gate Charge (V <sub>GS</sub> = -4.5V)	$Q_g$		9.5			
Total Gate Charge (V <sub>GS</sub> = -10V)	$Q_g$		19.4	_	nC	$V_{DS} = -30V, I_{D} = -5A$
Gate-Source Charge	$Q_{gs}$		2.3		IIC	
Gate-Drain Charge	$Q_{gd}$		3.6			
Turn-On Delay Time	t <sub>D(on)</sub>	_	3.7	_		$V_{GS}$ = -10V, $V_{DS}$ = -30V, $R_{GEN}$ = 6 $\Omega$ , $I_{D}$ = -5A
Turn-On Rise Time	t <sub>r</sub>	_	6.3	_	nS	
Turn-Off Delay Time	$t_{D(off)}$	_	58.7	_	113	
Turn-Off Fall Time	t <sub>f</sub>		26.1			
Body Diode Reverse Recovery Time	t <sub>rr</sub>	_	14.85	_	nS	I <sub>S</sub> = -5A, dI/dt = 100A/µs
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>		8.8	_	nC	I <sub>S</sub> = -5A, dI/dt = 100A/μs

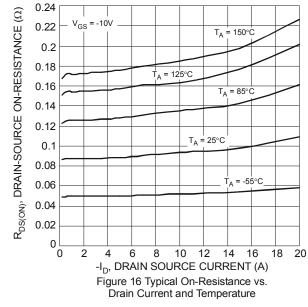
Notes: 5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.

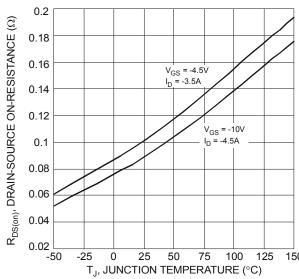
Device mounted on FR-4 substrate PC board, 20z copper, with minimum recommended be
 Device mounted on FR-4 substrate PC board, 20z copper, with 1inch square copper plate.
 UIS in production with L = 0.1mH, starting T<sub>A</sub> = +25°C.
 Short duration pulse test used to minimize self-heating effect.
 Guaranteed by design. Not subject to product testing.





20  $V_{DS} = -5.0V$ 18 16 ID, DRAIN CURRENT (A) 14 12 10 8 6 4 T<sub>A</sub> = 150°C 2 -55°C 0 2.5 3 3.5 4.5 5  $V_{GS}$ , GATE-SOURCE VOLTAGE (V) Figure 14 Typical Transfer Characteristics







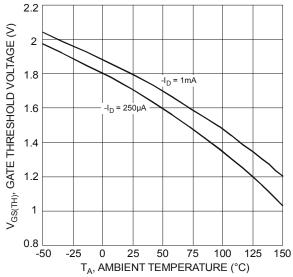
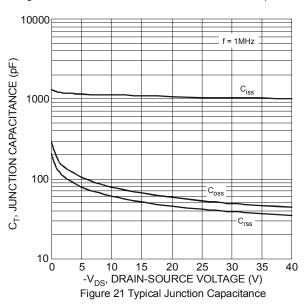
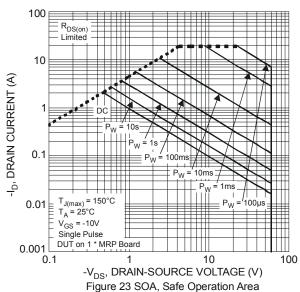
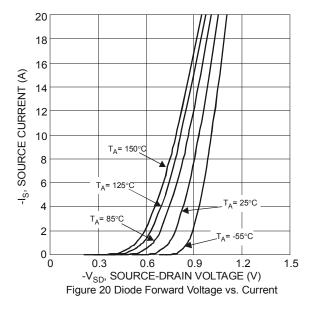
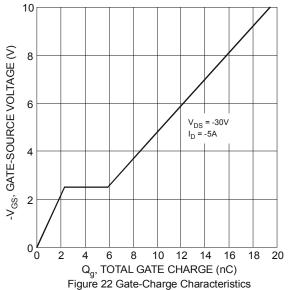


Figure 19 Gate Threshold Variation vs. Ambient Temperature





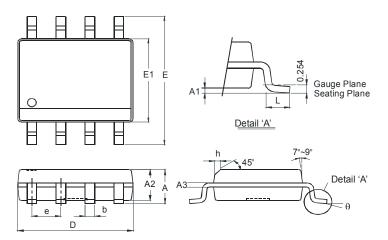






# **Package Outline Dimensions**

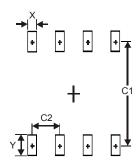
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.



SO-8						
Dim	Min	Max				
Α	1	1.75				
<b>A</b> 1	0.10	0.20				
A2	1.30	1.50				
A3	0.15	0.25				
b	0.3	0.5				
D	4.85	4.95				
Е	5.90	6.10				
E1	3.85	3.95				
е	1.27 Typ					
h	1	0.35				
L	0.62	0.82				
θ	0°	8°				
All Dimensions in mm						

# **Suggested Pad Layout**

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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